

**Search Notes**

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Examiner

Le Nguyen

Applicant(s)/Patent under  
Reexamination

HUNLETH ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EPO, JPO	9/27/2007	LVN
US-PGPub, USPAT: 715/838,708,711,767,802,822,823, 859,860,719-732,716,739; 725/37-61	9/27/2007	LVN